



---

**PRODUCT BULLETIN**  
Generic Copy

---

**12-APR-2002**

**SUBJECT: ON Semiconductor Product Bulletin #12405**

**TITLE: NLAS4599/NLAST4599 Datasheet Error Correction**

**EFFECTIVE DATE: 12-Apr-2002**

**AFFECTED PRODUCT DIVISION: Logic Products Div**

**ADDITIONAL RELIABILITY DATA:** None

**SAMPLES:** No

**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact Sales Office or Tom Bruner <[RPP920@onsemi.com](mailto:RPP920@onsemi.com)>

**DISCLAIMER:**

ON Semiconductor considers this change approved unless specific conditions of acceptance are provided in writing. To do so, contact your local ON Semiconductor sales office.

**DESCRIPTION AND PURPOSE:**

ON Semiconductor wishes to inform our customers that a correction is being made to the existing datasheets for the NLAS4599DFT2, NLAS4599DTT1, NLAST4599DFT2 and NLAST4599DTT1 devices. The change being made pertains to an existing test condition and the addition of a new test condition. The changes are:

1) Change the Vcc Test Condition for the Iin Parameter from Vcc=0V to 5.5V to Vcc=2.0V to 5.5V. This is currently on Page 3 of the datasheet. The Guaranteed Limit will not change.

2) Add an Ioff test to the datasheet. The Vcc test condition will be at Vcc=0V, with the Guaranteed Limits at +/- 10uA across all temperatures.

This corrects these datasheets in accordance with the design used for these parts and meets the JEDEC JESD64 publication standard, which is the CMOS Logic Low Voltage with OVT specification Interface Standard.

**AFFECTED DEVICE LIST:**

**PART**

NLAS4599DFT2

NLAS4599DTT1

NLAST4599DFT2

NLAST4599DTT1